

N-channel 600 V, 0.68 Ω typ., 10 A, SuperMESH™ Power MOSFET in a TO-220FP ultra narrow leads package

Datasheet - production data

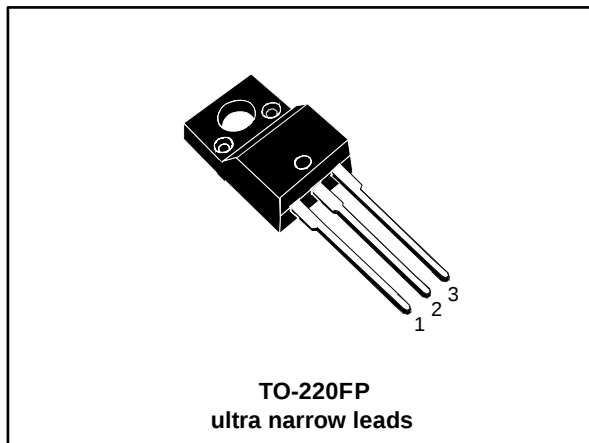
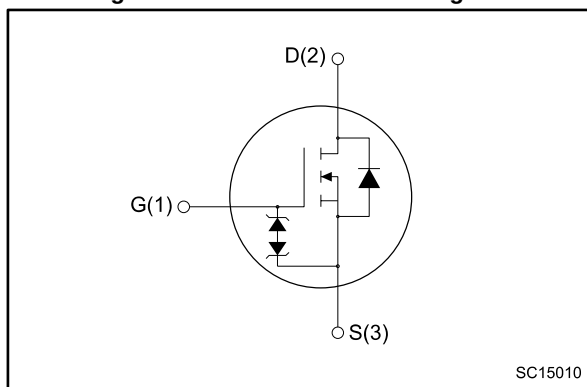


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D	P _{tot}
STFU10NK60Z	600 V	0.75 Ω	10 A	35 W

- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Zener-protected

Applications

- Switching applications

Description

This high voltage device is a Zener-protected N-channel Power MOSFET developed using the SuperMESH™ technology by STMicroelectronics, an optimization of the well-established PowerMESH™. In addition to a significant reduction in on-resistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.

Table 1: Device summary

Order code	Marking	Package	Packaging
STFU10NK60Z	10NK60Z	TO-220FP ultra narrow leads	Tube

Contents

1	Electrical ratings	3
2	Electrical characteristics	4
	2.1 Electrical characteristics (curves).....	6
3	Test circuits	9
4	Package information	10
	4.1 TO-220FP ultra narrow leads package information.....	10
5	Revision history	12

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate-source voltage	± 30	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$	10	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$	5.7	A
$I_{DM}^{(2)}$	Drain current (pulsed)	36	A
P_{TOT}	Total dissipation at $T_C = 25\text{ }^{\circ}\text{C}$	35	W
ESD	Gate-source, human body model ($R = 1.5\text{ k}\Omega$, $C = 100\text{ pF}$)	4	kV
$dv/dt^{(3)}$	Peak diode recovery voltage slope	4.5	V/ns
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink ($t = 1\text{ s}$; $T_C = 25\text{ }^{\circ}\text{C}$)	2500	V
T_J	Operation junction temperature range	-55 to 150	$^{\circ}\text{C}$
T_{stg}	Storage temperature range		

Notes:⁽¹⁾Limited by package⁽²⁾Pulse width limited by safe operating area⁽³⁾ $I_{SD} < 10\text{ A}$, $di/dt < 200\text{ A}/\mu\text{s}$, $V_{DD} = 80\% V_{(BR)DSS}$

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	3.6	$^{\circ}\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	$^{\circ}\text{C}/\text{W}$

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max)	10	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25\text{ }^{\circ}\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	300	mJ

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 5: On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	V _{GS} = 0 V, I _D = 250 μA	600			V
I _{DSS}	Zero gate voltage drain current	V _{GS} = 0 V, V _{DS} = 600 V			1	μA
		V _{GS} = 0 V, V _{DS} = 600 V, T _C = 125 °C ⁽¹⁾			50	μA
I _{GSS}	Gate-body leakage current	V _{DS} = 0 V, V _{GS} = +20 V			±10	μA
V _{GS(th)}	Gate threshold voltage	V _{DS} = V _{GS} , I _D = 250 μA	3	3.75	4.5	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 4.5 A		0.68	0.75	Ω

Notes:

⁽¹⁾Defined by design, not subject to production test.

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C _{iss}	Input capacitance	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	-	1370	-	pF
C _{oss}	Output capacitance		-	156	-	pF
C _{rss}	Reverse transfer capacitance		-	37	-	pF
C _{oss eq} ⁽¹⁾	Equivalent output capacitance	V _{GS} = 0 V, V _{DS} = 0 to 480 V	-	93	-	pF
Q _g	Total gate charge	V _{DD} = 480 V, I _D = 8 A, V _{GS} = 10 V (see Figure 13: "Test circuit for gate charge behavior")	-	48	-	nC
Q _{gs}	Gate-source charge		-	8	-	nC
Q _{gd}	Gate-drain charge		-	25	-	nC

Notes:

⁽¹⁾C_{oss eq} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80%

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t _{d(on)}	Turn-on delay time	V _{DD} = 300 V, I _D = 4 A, R _G = 4.7 Ω, V _{GS} = 10 V (see Figure 12: "Test circuit for resistive load switching times" and Figure 17: "Switching time waveform")	-	20	-	ns
t _r	Rise time		-	20	-	ns
t _{d(off)}	Turn-off delay time		-	55	-	ns
t _f	Fall time		-	30	-	ns

Table 8: Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)}$	Source-drain current		-		10	V
$I_{SDM}^{(2)}$	Source-drain current (pulsed)		-		36	A
$V_{SD}^{(3)}$	Forward on voltage	$I_{SD} = 10\text{ A}$, $V_{GS} = 0\text{ V}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 8\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 40\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$ (see Figure 14: "Test circuit for inductive load switching and diode recovery times")	-	570		ns
Q_{rr}	Reverse recovery charge		-	4.1		μC
I_{RRM}	Reverse recovery current		-	15		A

Notes:⁽¹⁾Limited by package⁽²⁾Pulse width limited by safe operating area⁽³⁾Pulsed: pulse duration = 300 μs , duty cycle 1.5%

Table 9: Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1\text{ mA}$, $I_D = 0\text{ A}$	± 30	-	-	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

2.1 Electrical characteristics (curves)

Figure 2: Safe operating area

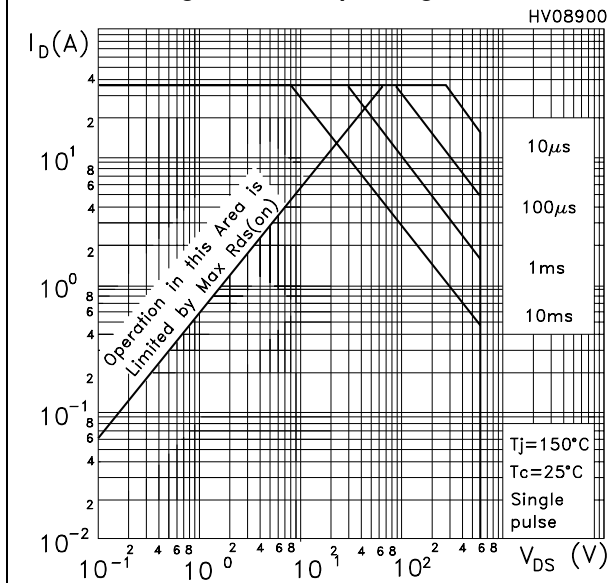


Figure 3: Thermal impedance

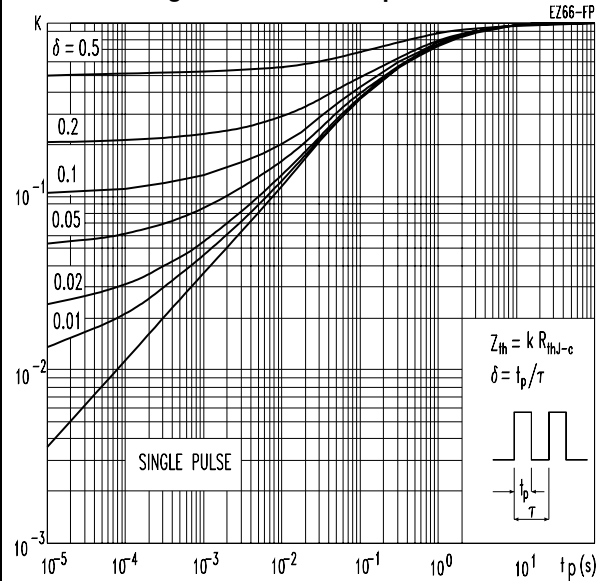


Figure 4: Output characteristics

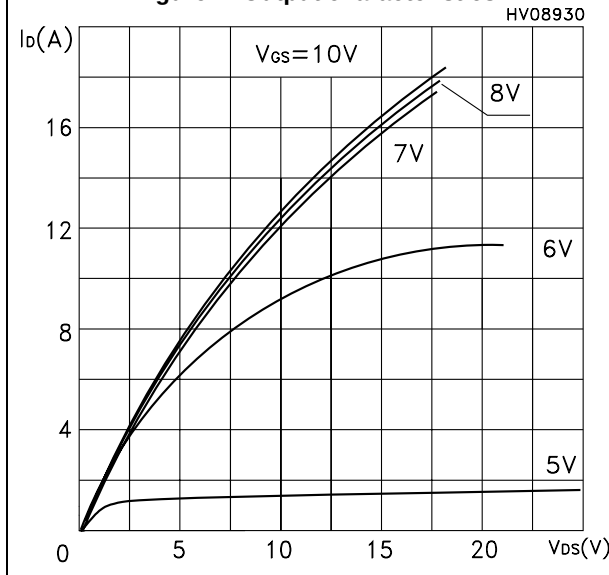


Figure 5: Gate charge vs gate-source voltage

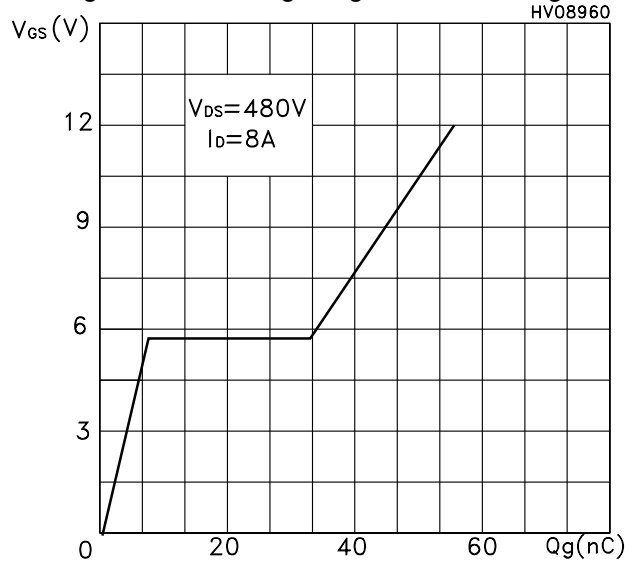


Figure 6: Capacitance variations

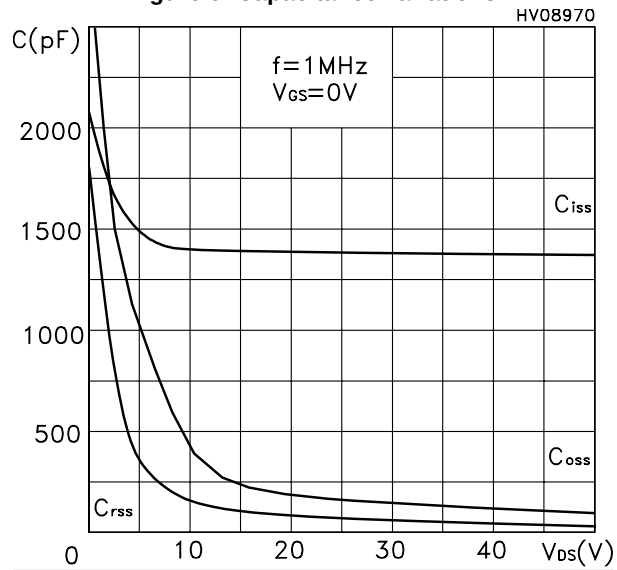


Figure 7: Static drain-source on-resistance

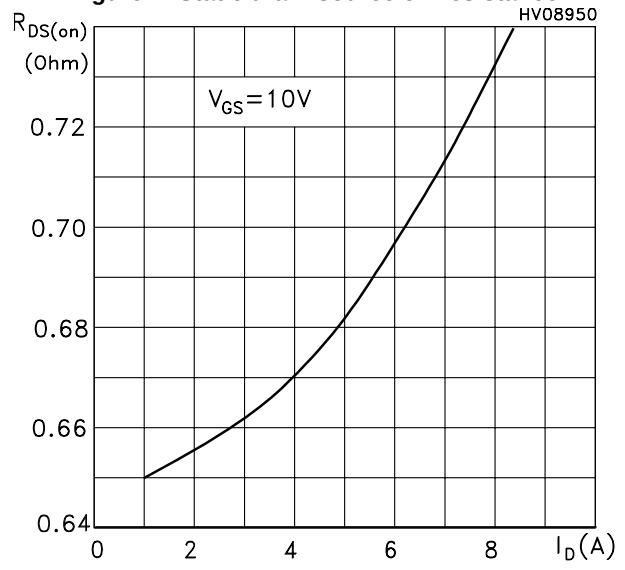


Figure 8: Normalized gate threshold voltage vs temperature

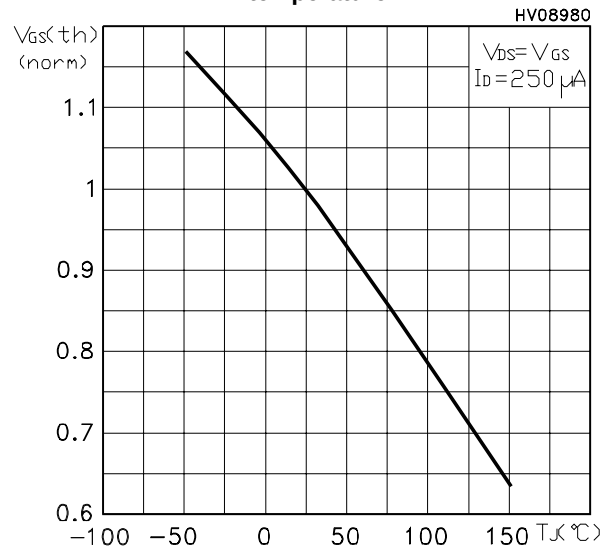


Figure 9: Normalized on-resistance vs temperature

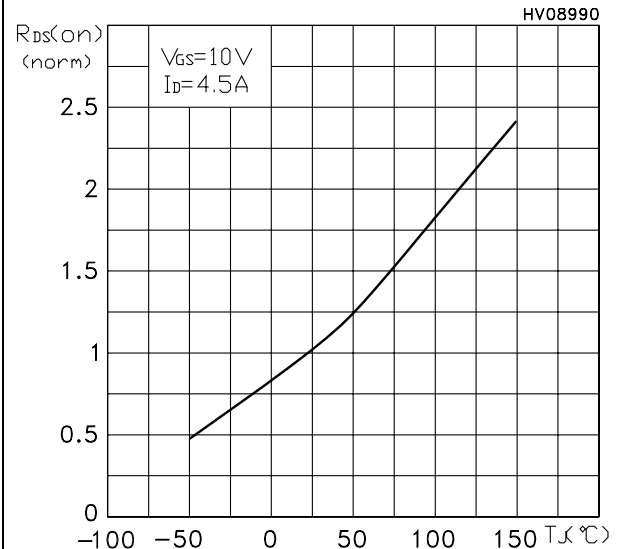


Figure 10: Source-drain diode forward characteristics

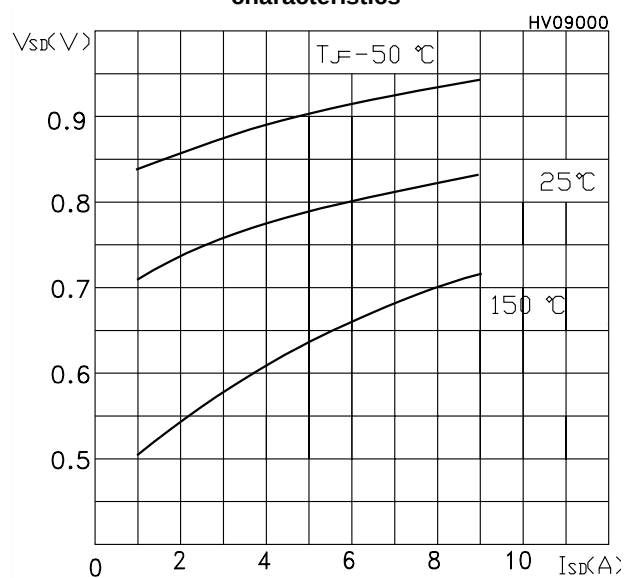
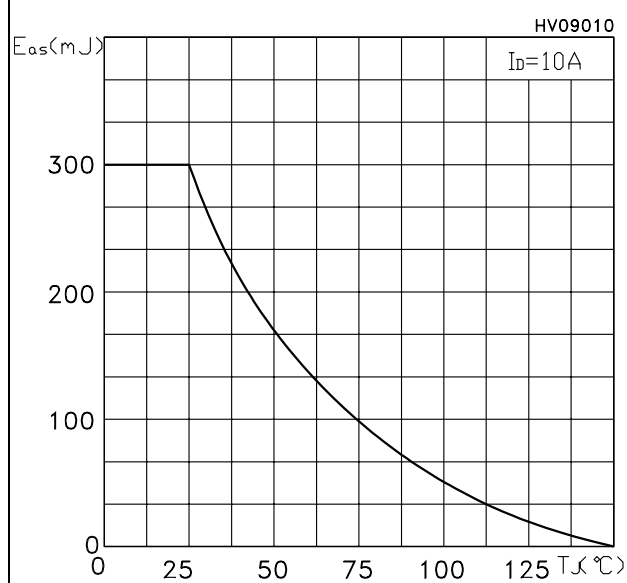
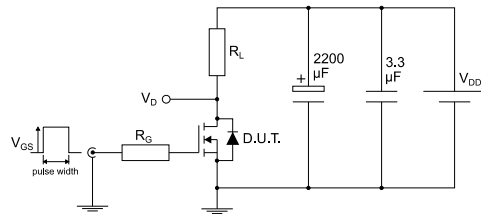


Figure 11: Maximum avalanche energy



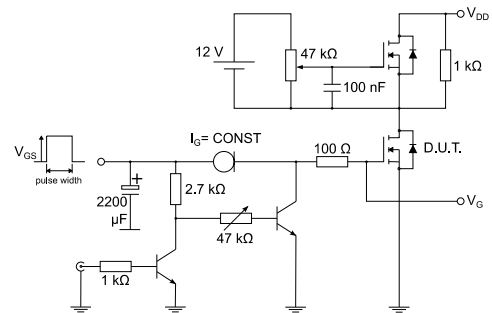
3 Test circuits

Figure 12: Test circuit for resistive load switching times



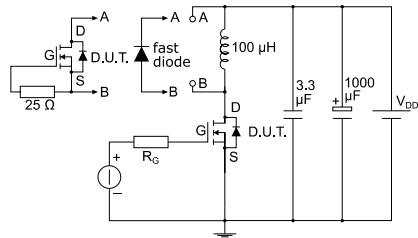
AM01468v1

Figure 13: Test circuit for gate charge behavior



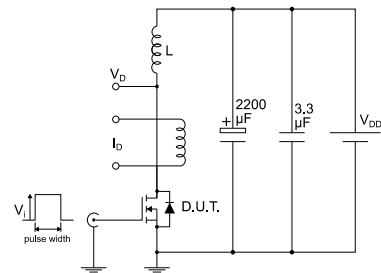
AM01469v1

Figure 14: Test circuit for inductive load switching and diode recovery times



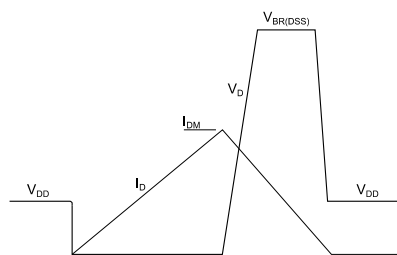
AM01470v1

Figure 15: Unclamped inductive load test circuit



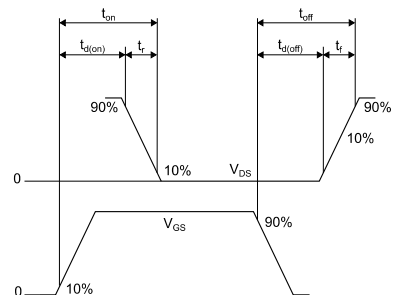
AM01471v1

Figure 16: Unclamped inductive waveform



AM01472v1

Figure 17: Switching time waveform



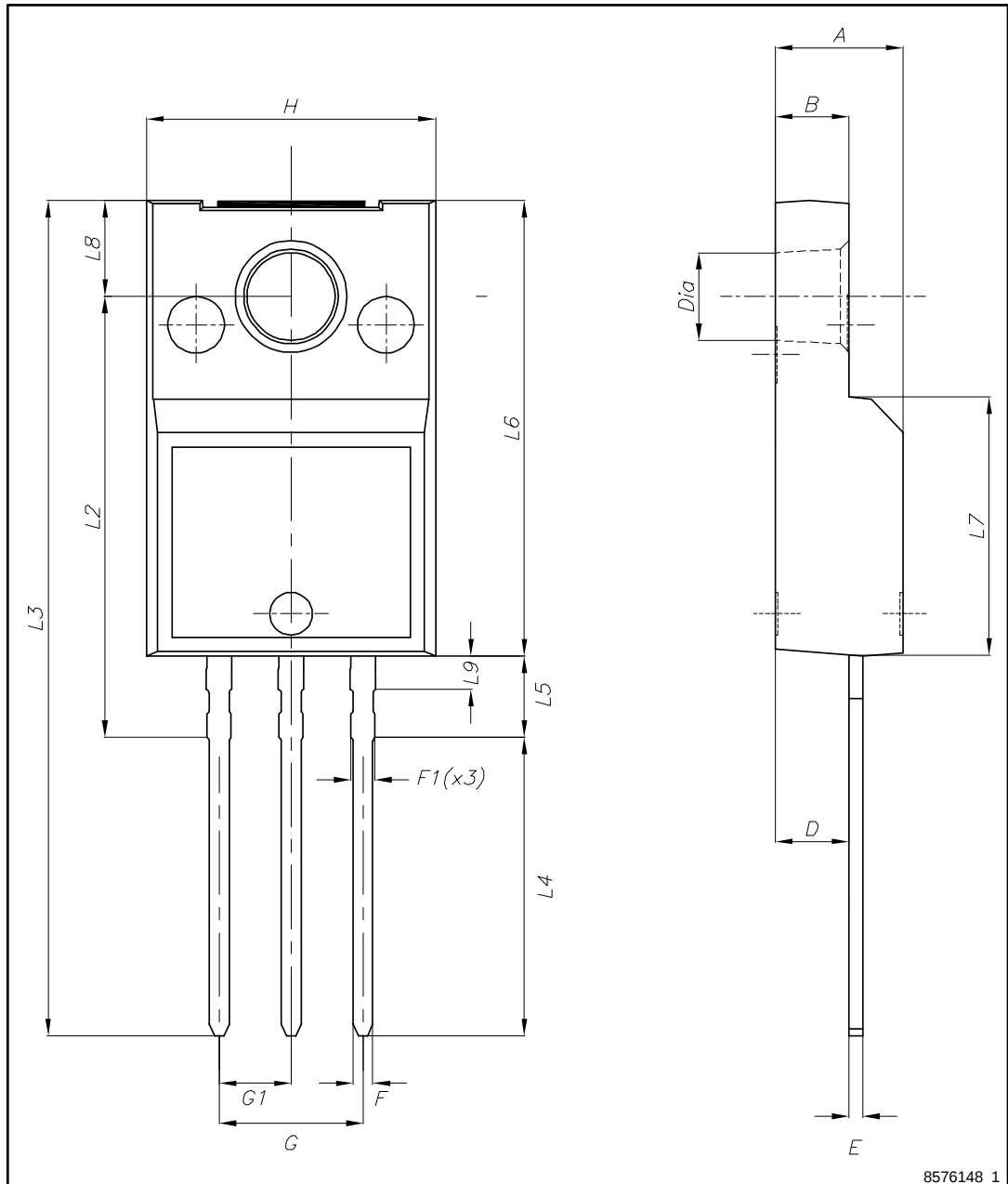
AM01473v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 TO-220FP ultra narrow leads package information

Figure 18: TO-220FP ultra narrow leads package outline



8576148_1

Table 10: TO-220FP ultra narrow leads mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
E	0.45		0.60
F	0.65		0.75
F1	-		0.90
G	4.95		5.20
G1	2.40	2.54	2.70
H	10.00		10.40
L2	15.10		15.90
L3	28.50		30.50
L4	10.20		11.00
L5	2.50		3.10
L6	15.60		16.40
L7	9.00		9.30
L8	3.20		3.60
L9	-		1.30
Dia.	3.00		3.20

5 Revision history

Table 11: Document revision history

Date	Revision	Changes
07-Jan-2016	1	Initial release.
12-Sep-2016	2	Document status changed from preliminary to production data. Minor text changes.
05-Dec-2016	3	Updated Features on cover page. Updated Table 2: "Absolute maximum ratings" and added Table 4: "Avalanche characteristics" . Updated Table 5: "On /off states" , Table 6: "Dynamic" , Table 8: "Source drain diode" and Table 9: "Gate-source Zener diode" . Minor text changes

IMPORTANT NOTICE – PLEASE READ CAREFULLY

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2016 STMicroelectronics – All rights reserved